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Title: SEMICONDUCTOR MEMORY
DEVICE AND SEMICONDUCTOR
MEMORY DEVICE CONTROL
METHOD
Inventor(s): Hiroyuki TAKAHASHI, et al.
DOCKET NO.: 029471-0168

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FIG . 1

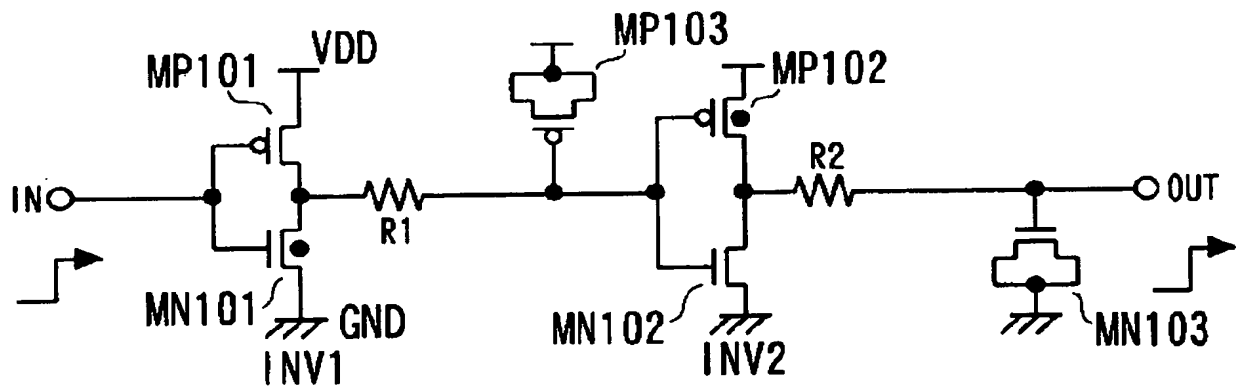


FIG . 2

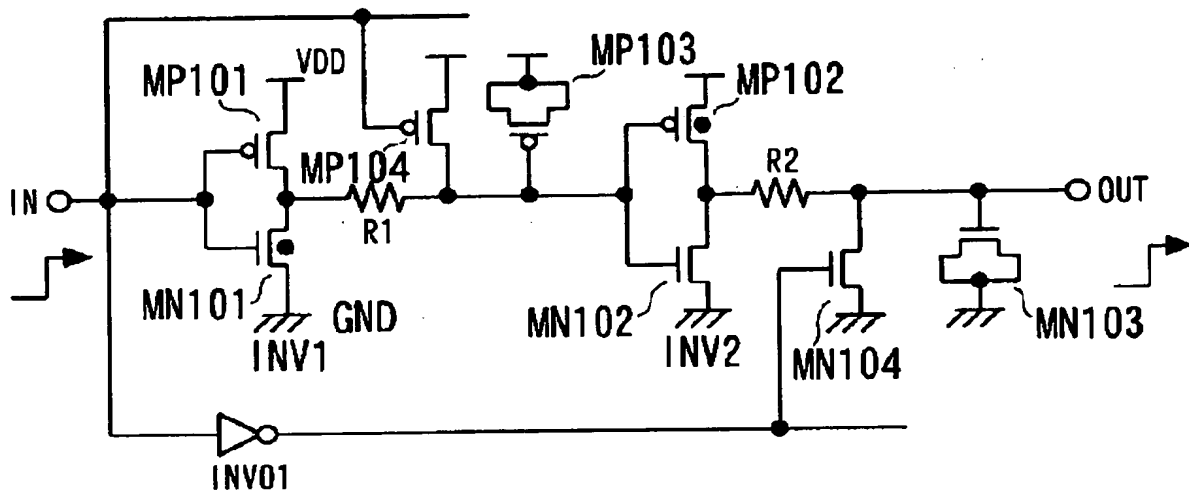


FIG . 3

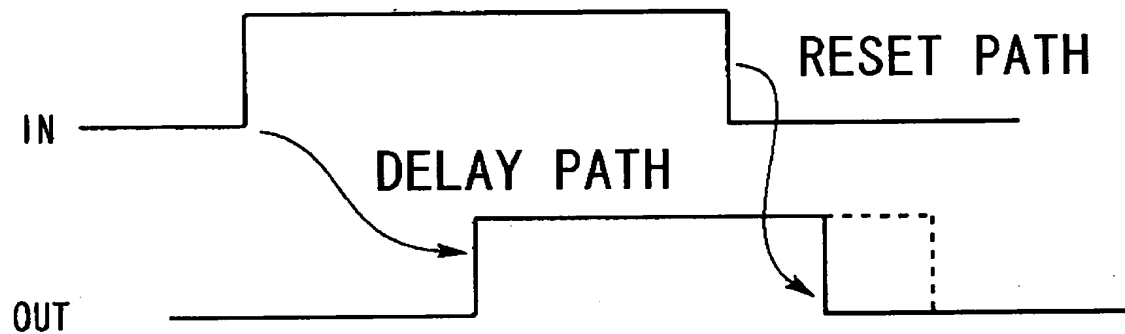


FIG . 4

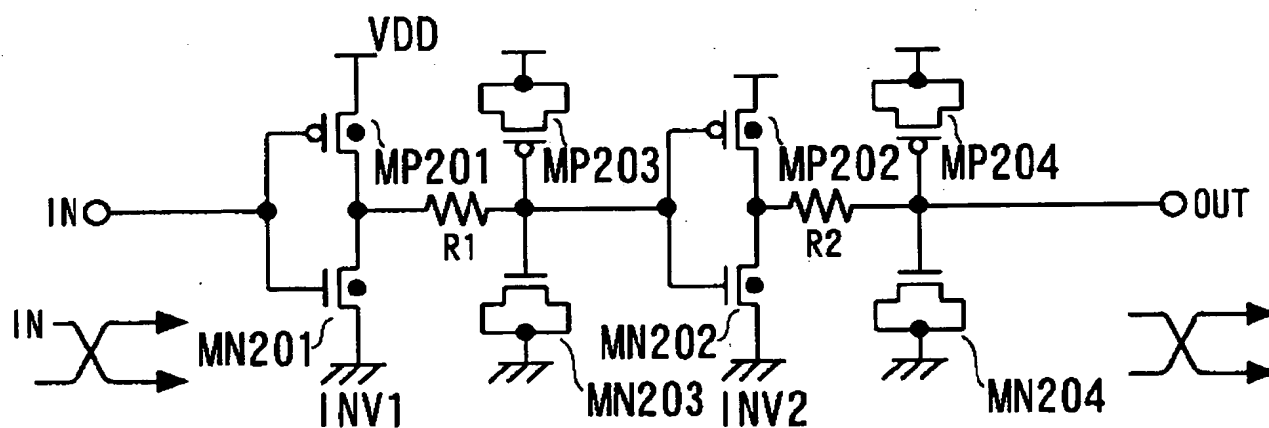


FIG. 5

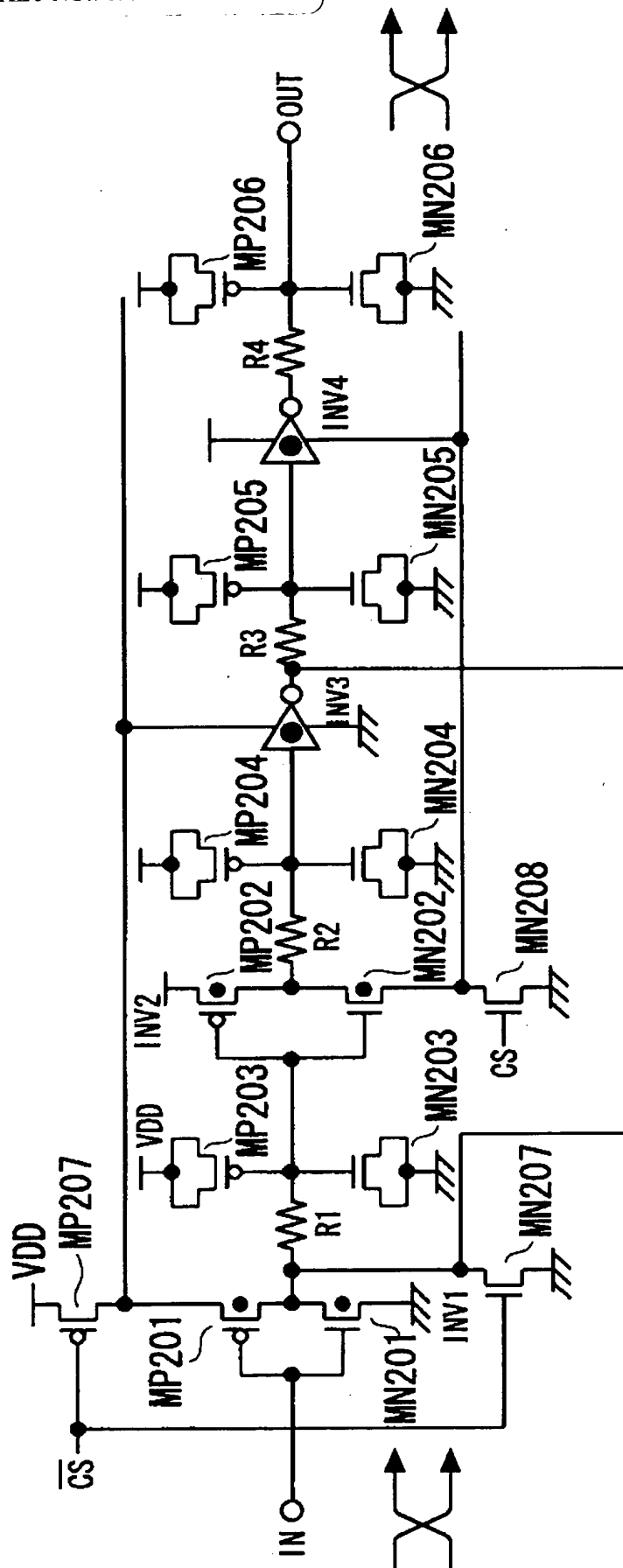


FIG. 6

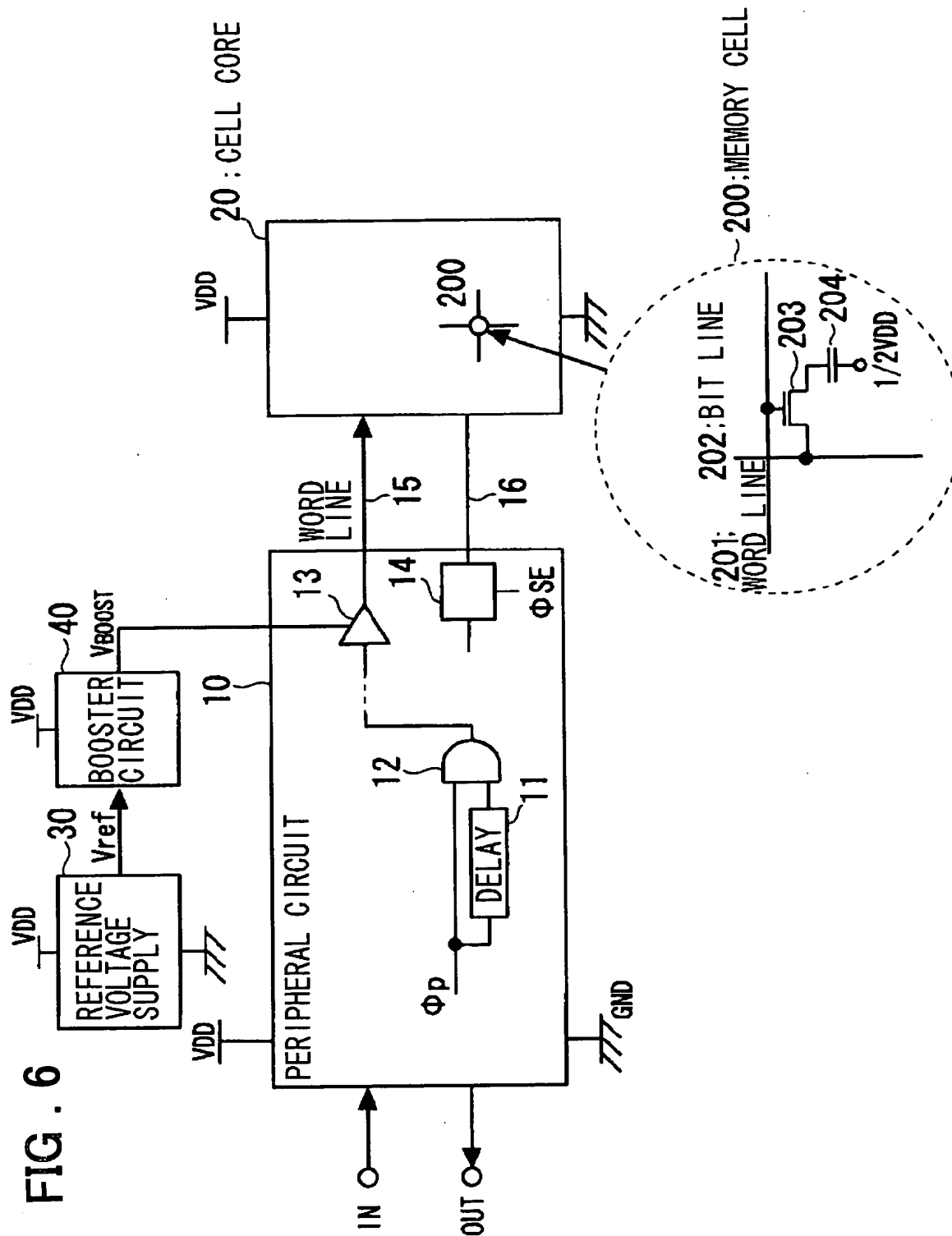


FIG . 7

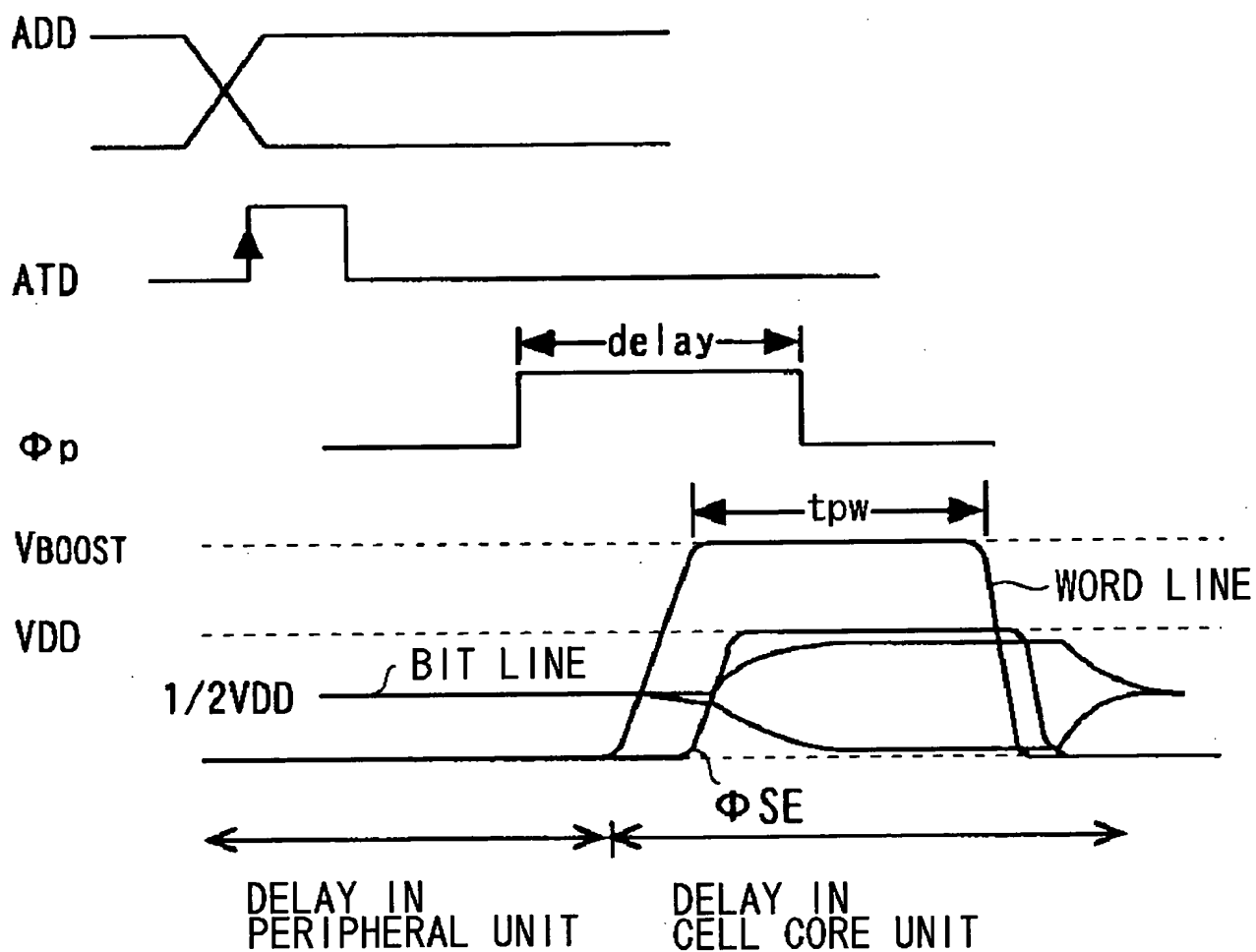


FIG . 8

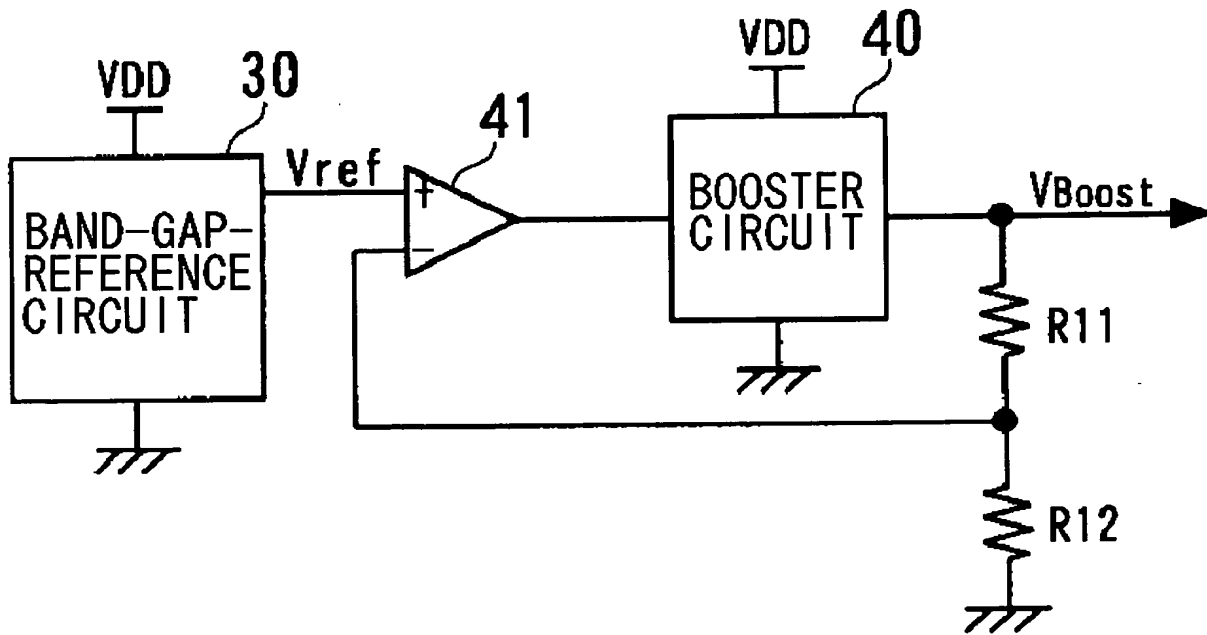


FIG . 9

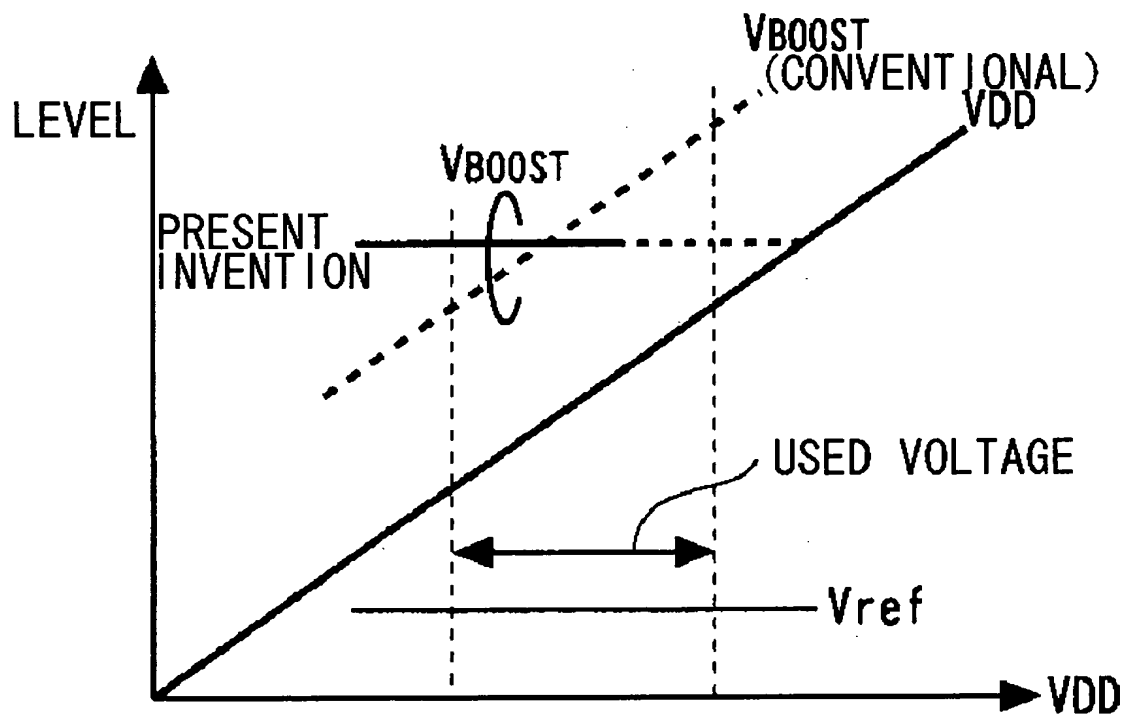


FIG . 10

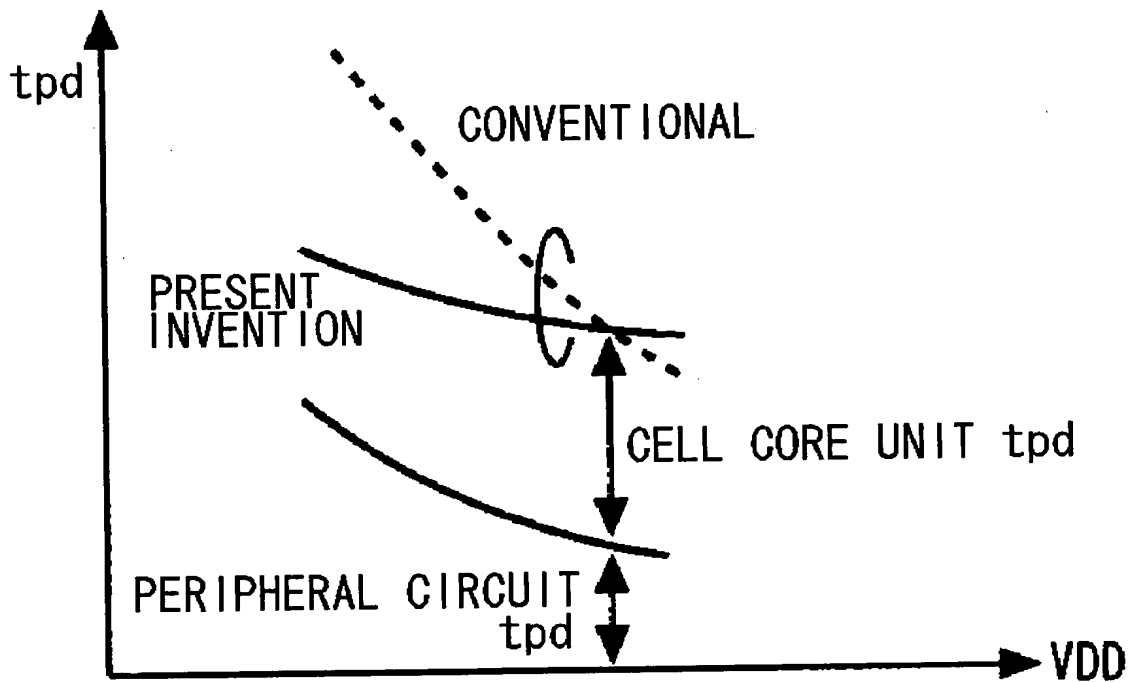


FIG . 11

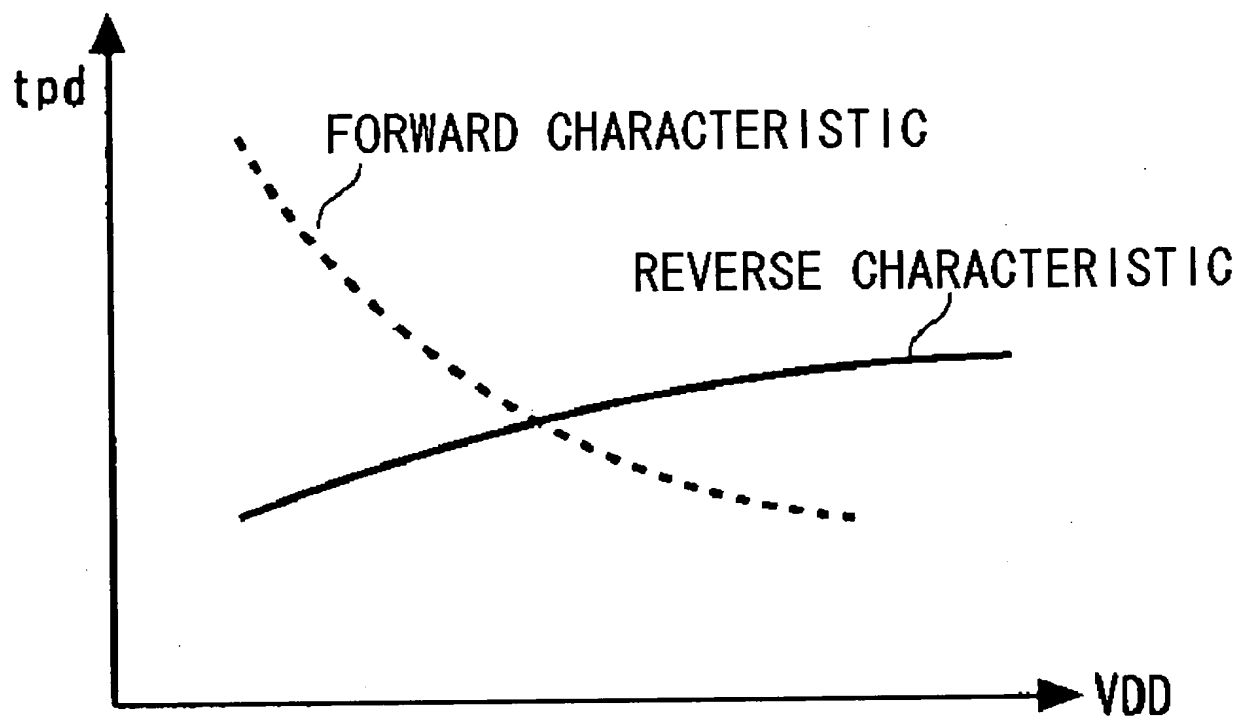


FIG . 12

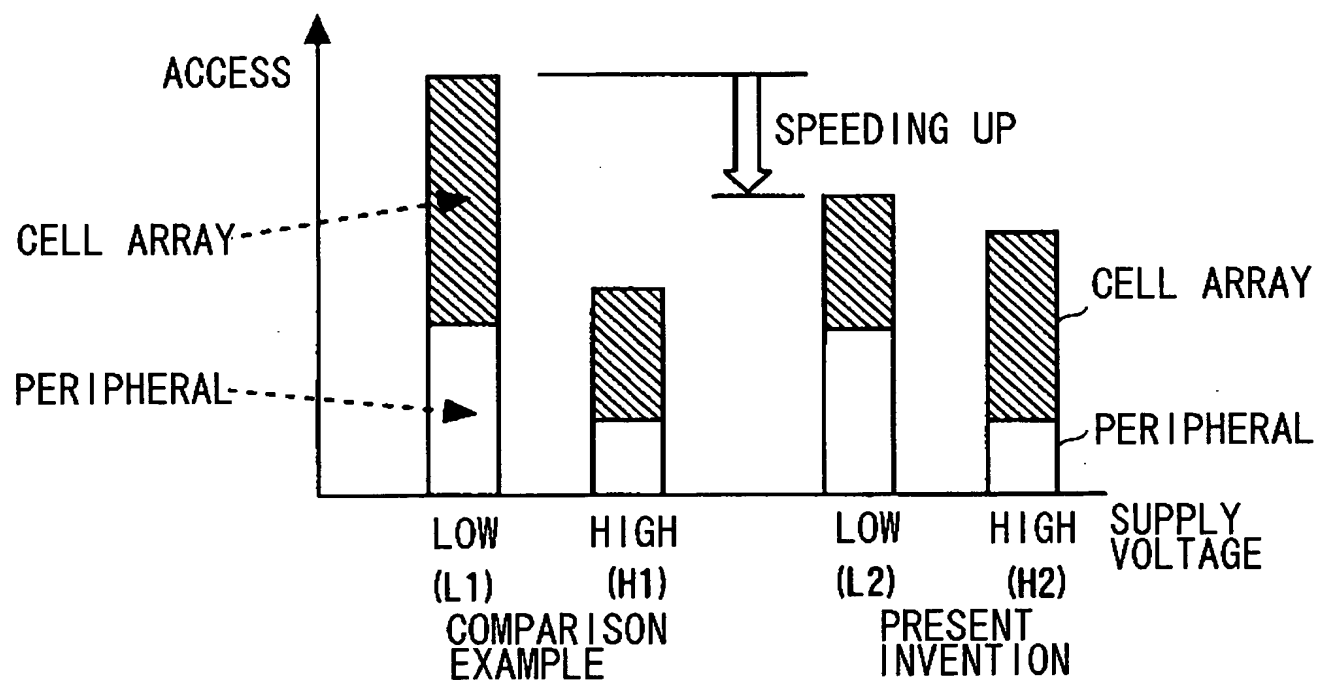
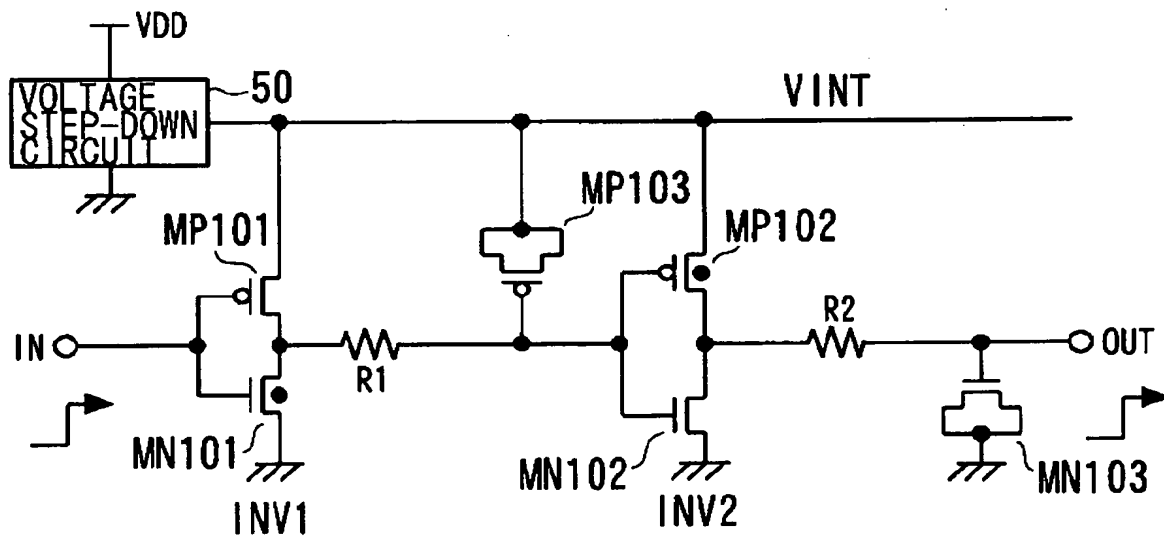


FIG . 13



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FIG. 14

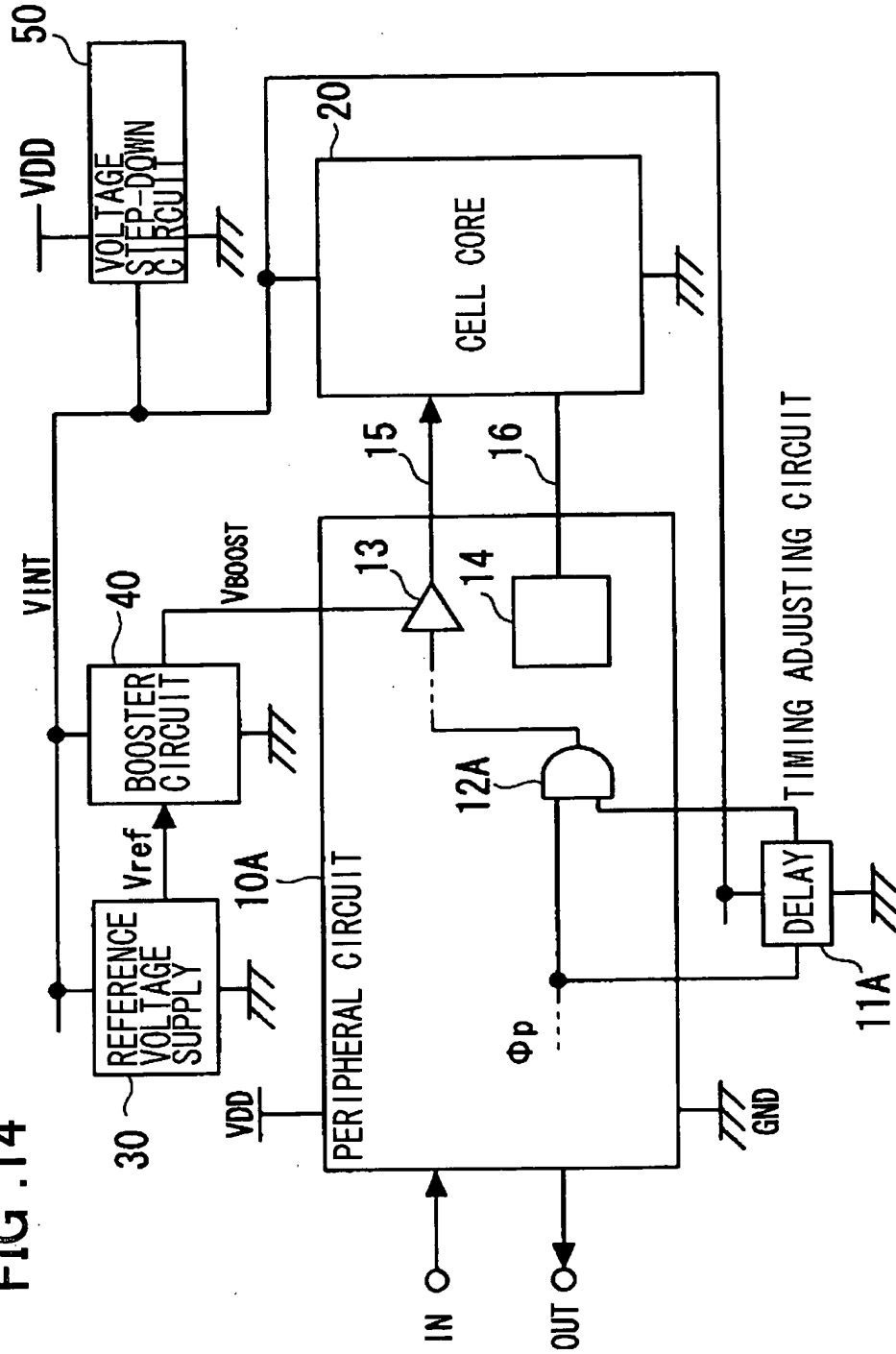


FIG. 15A PRIOR ART

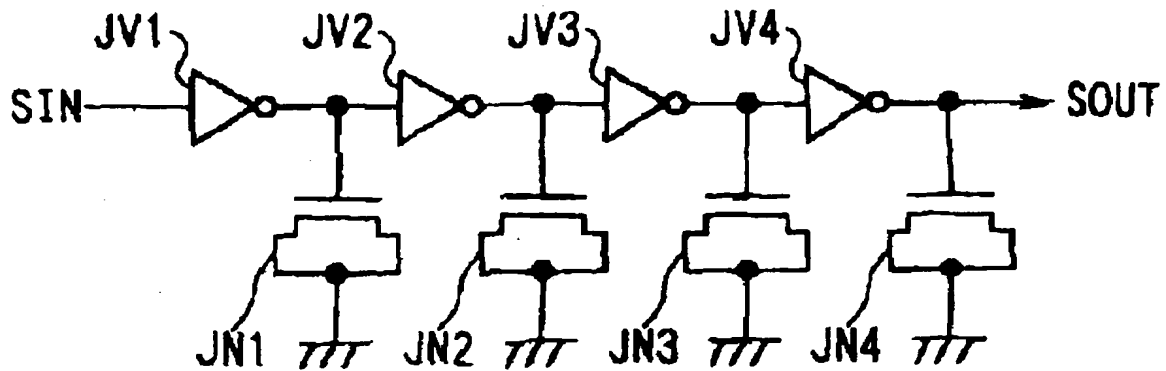


FIG. 15B PRIOR ART

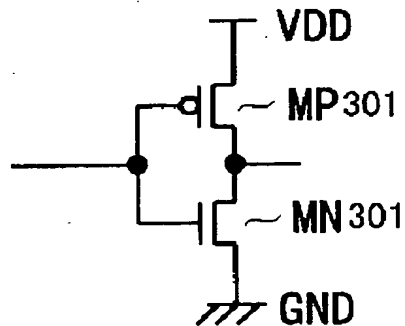


FIG . 16

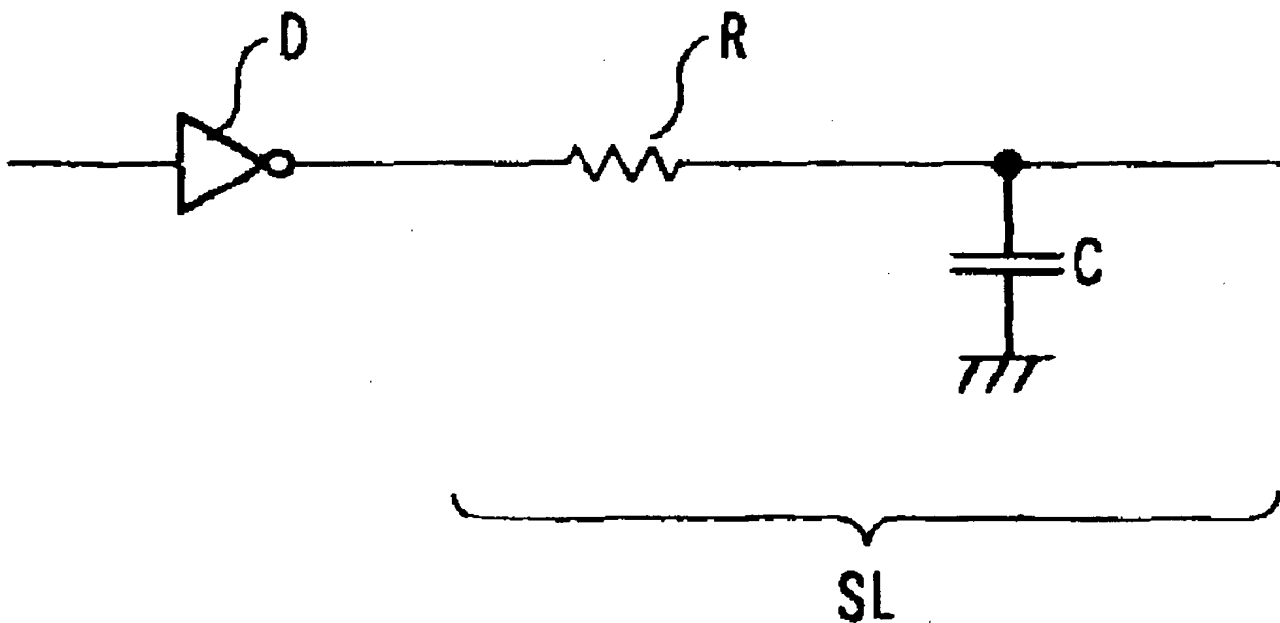


FIG . 17 PRIOR ART

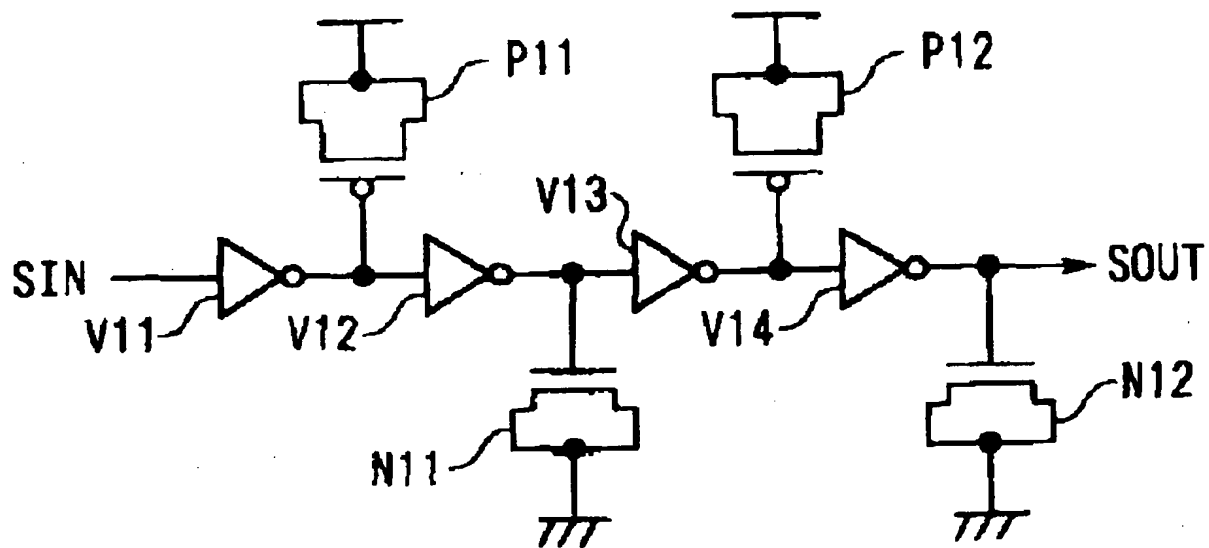


FIG. 18 PRIOR ART

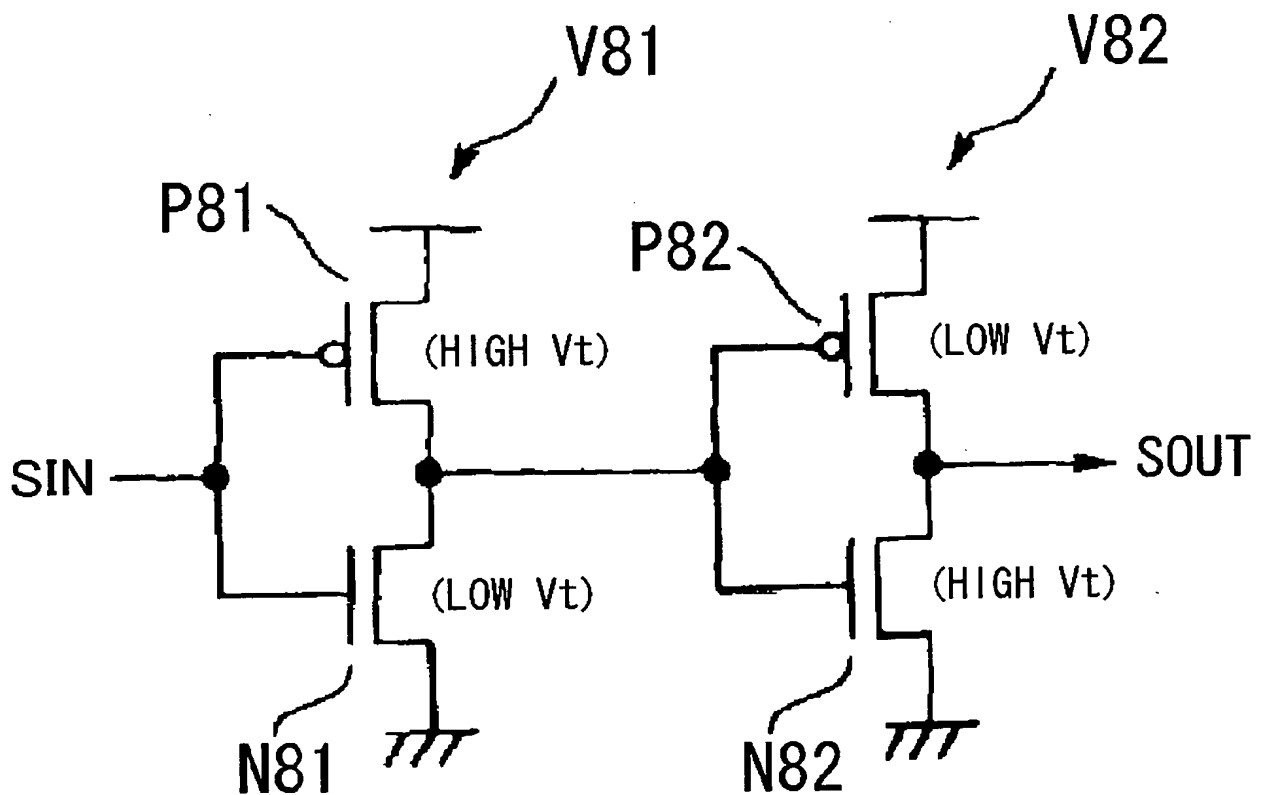
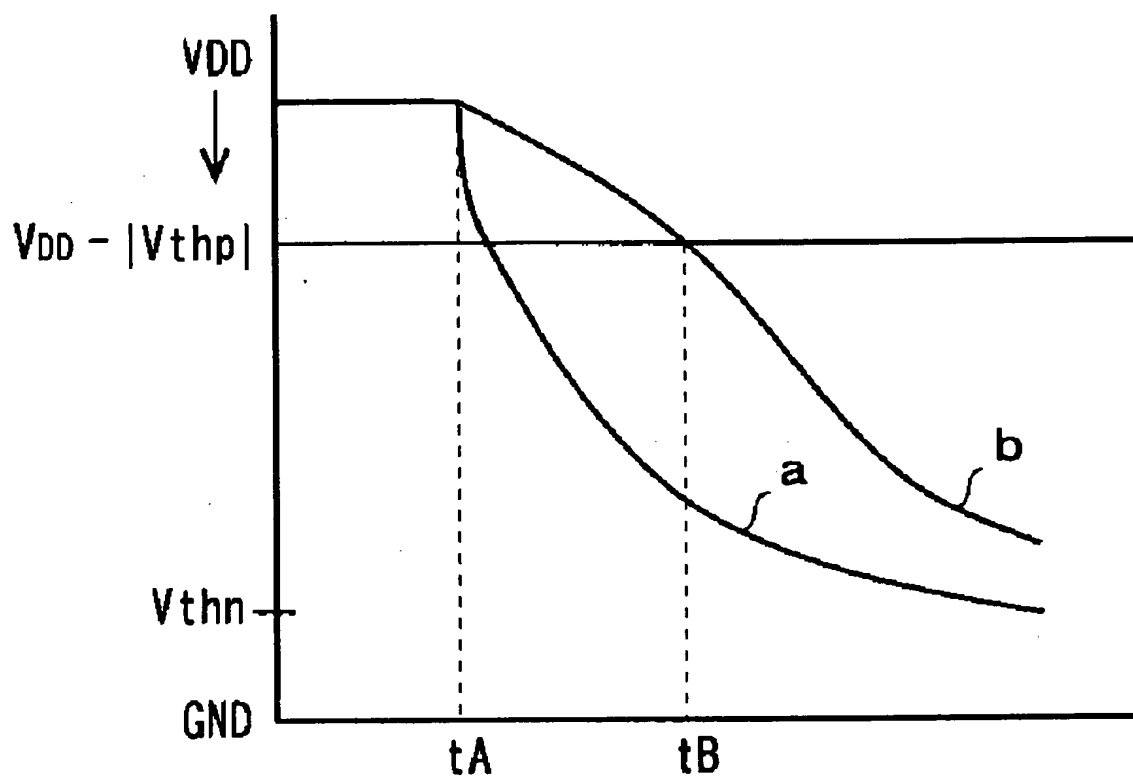


FIG . 19



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